

PRELIMINARY AMENDMENT

PATENT APPLICATION

REMARKS

The foregoing amendments have been made to ensure correct dependencies in the claims, and to ensure that the Examiner receives a copy of the Abstract, which was part of the publication of this PCT application. Early, favorable consideration on the merits is respectfully requested.

Respectfully submitted,



Frank L. Bernstein
Registration No. 31,484

SUGHRUE MION, PLLC
1010 El Camino Real, Suite 360
Menlo Park, CA 94025

Tel: (650) 325-5800
Fax: (650) 325-6606

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APPENDIX

VERSION WITH MARKINGS TO SHOW CHANGES MADE

IN THE SPECIFICATION:

The specification is changed as follows:

IN THE CLAIMS:

The claims are amended as follows:

3. (Amended) The charged particle device (1) according to claim 1 [or 2] wherein the drift region (26) reaching from the back surface (28) to the front surface (27) is positioned away from the geometrical center (40) of the mirror.

4. (Amended) The charged particle device (1) according to [one of the preceding claims] claim 1 further comprising a deflection unit (12C) for directing the charged particle beam essentially along the optical axis of the objective lens, said deflection unit (12C) being arranged between the particle mirror (14) and the objective lens (10).

6. (Amended) The charged particle device (1) according to [one of the preceding] claim 1 wherein the particle mirror (14) is tilted with regard to the optical axis (6) by an [angel] angle α between about 20 and about 70 [degree] degrees, preferably between about 40 and about 50 [degree] degrees, most preferably about 45 [degree] degrees.

7. (Amended) The charged particle device (1) according to [one of the preceding claims] claim 1 wherein the particle mirror (14) comprises a conductive surface (21) or a conductive deflecting grid (41) kept on a predetermined potential sufficient to deflect all particles having less than a predetermined energy.

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9. (Amended) The charged particle device (1) according to claim 7 [or 8] wherein the particle mirror (14) comprises a particle absorber (23) for absorbing particles having more than the predetermined energy.

10. (Amended) The charged particle device (1) according to claim 7 [or 8] wherein a second detector (24) is arranged behind the conductive deflecting grid (41) for detecting particles having more than the predetermined energy.

11. (Amended) The charged particle device (1) according to [one of the preceding claims] claim 1 wherein a high pass filter (3) is arranged in front of the detector (16), allowing only particles having an energy above a predetermined energy to enter the detector.

13. (Amended) The charged particle device (1) according to [one of the preceding claims] claim 1 wherein said drift region (26) is positioned away from the optical axis (6) of the objective lens (10), so that all charged [particle] particles coming from the specimen within an angle $\gamma \leq 5$ [degree] degrees, preferably ≤ 10 [degree] degrees, as measured from the optical axis (6) of the objective lens (10), hit the deflecting region (25) of the mirror (14).

17. (Amended) The particle mirror (14) according to claim 15 [or 16] wherein the particle mirror (14) further comprises a particle absorber (23) for absorbing particles having more than the predetermined energy.

18. (Amended) The particle mirror (14) according to [one of claims 14 to 17] claim 14 wherein deflecting region (25) deflects the particles, so that the angle between the outgoing path of the particle and the axes normal to the front surface of the mirror, at the point where the particle hits the mirror, equals the angle between the incoming path of the particle and the axes normal to the front surface of the mirror.

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23. (Amended) The charged particle device (1) according to claim 21 [or 22] wherein the particle mirror (14) comprises a particle absorber (23) for absorbing particles having more than the predetermined energy.

24. (Amended) The charged particle device (1) according to [one of claims 20 to 23] claim 20 wherein the particle mirror (14) comprises a deflecting region (25) located on the front surface (27) for deflecting all particles in a given velocity range and in a given angular range, so that the angle β_o between the outgoing path of the particle and the axes normal to the front surface of the mirror, at the point where the particle hits the mirror, equals the angle β_i between the incoming path of the particle and the axes normal to the front surface of the mirror.

25. (Amended) The charged particle device (1) according to [one of claims 20 to 24] claim 20 wherein the particle mirror (14) is tilted with regard to the optical axis (6) by an [angel] angle α between about 20 and about 70 [degree] degrees, preferably between about 40 and about 50 [degree] degrees, most preferably about 45 [degree] degrees.

IN THE ABSTRACT OF DISCLOSURE:

The abstract has been added.